

METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

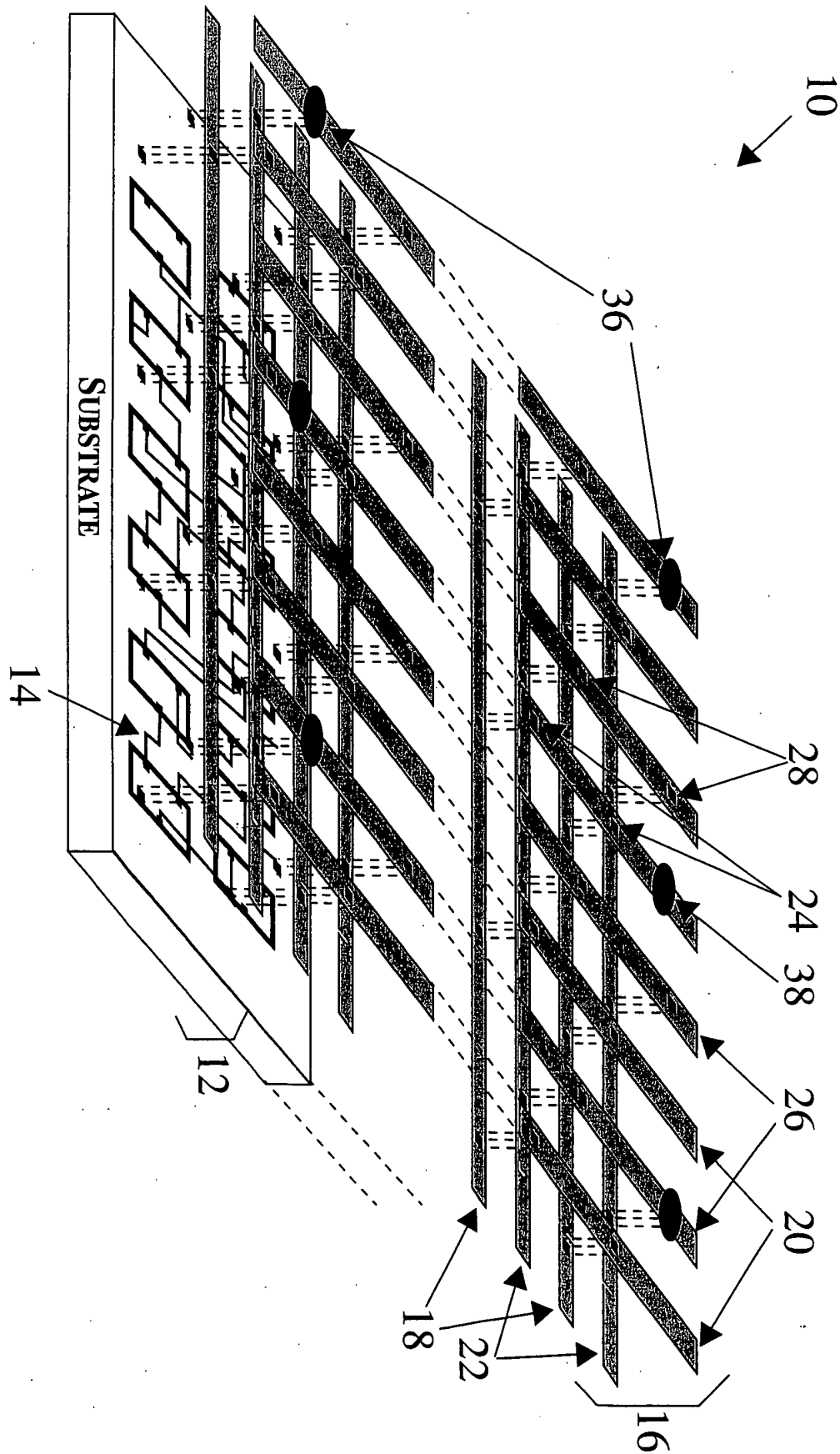


Figure 1

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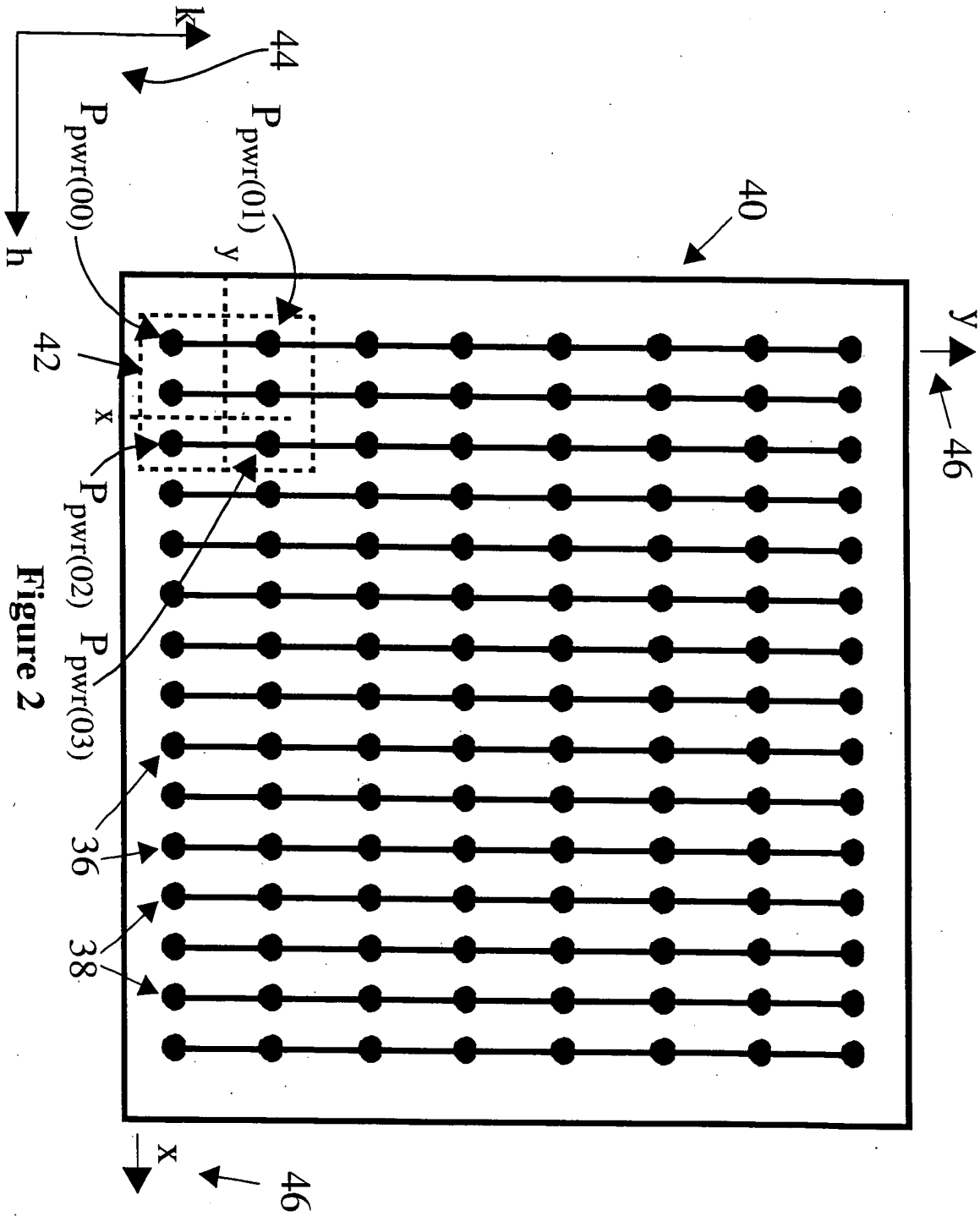


Figure 2

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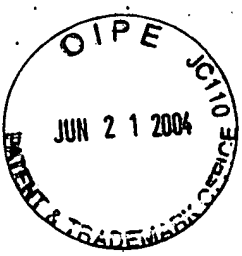
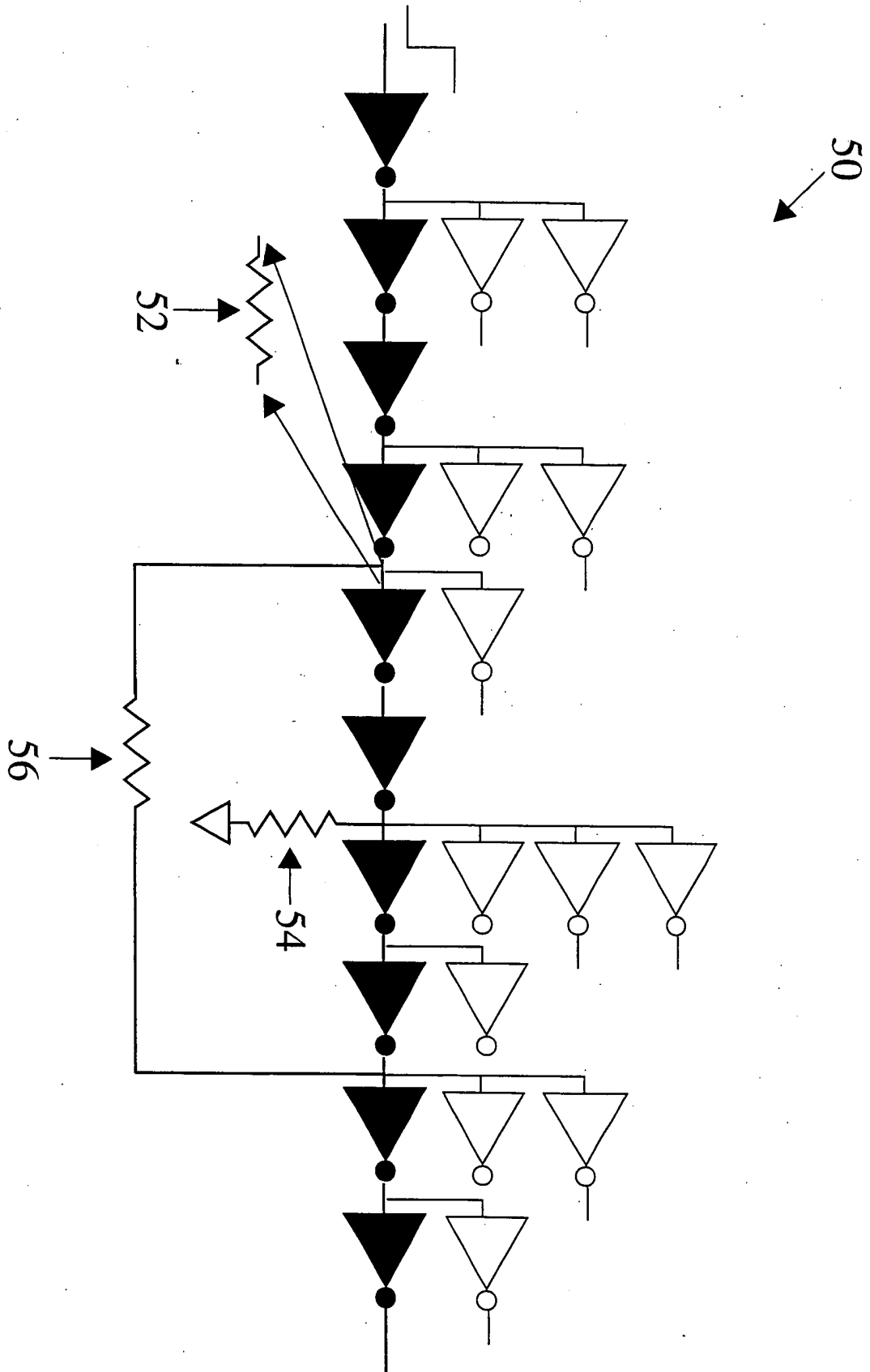


Figure 3



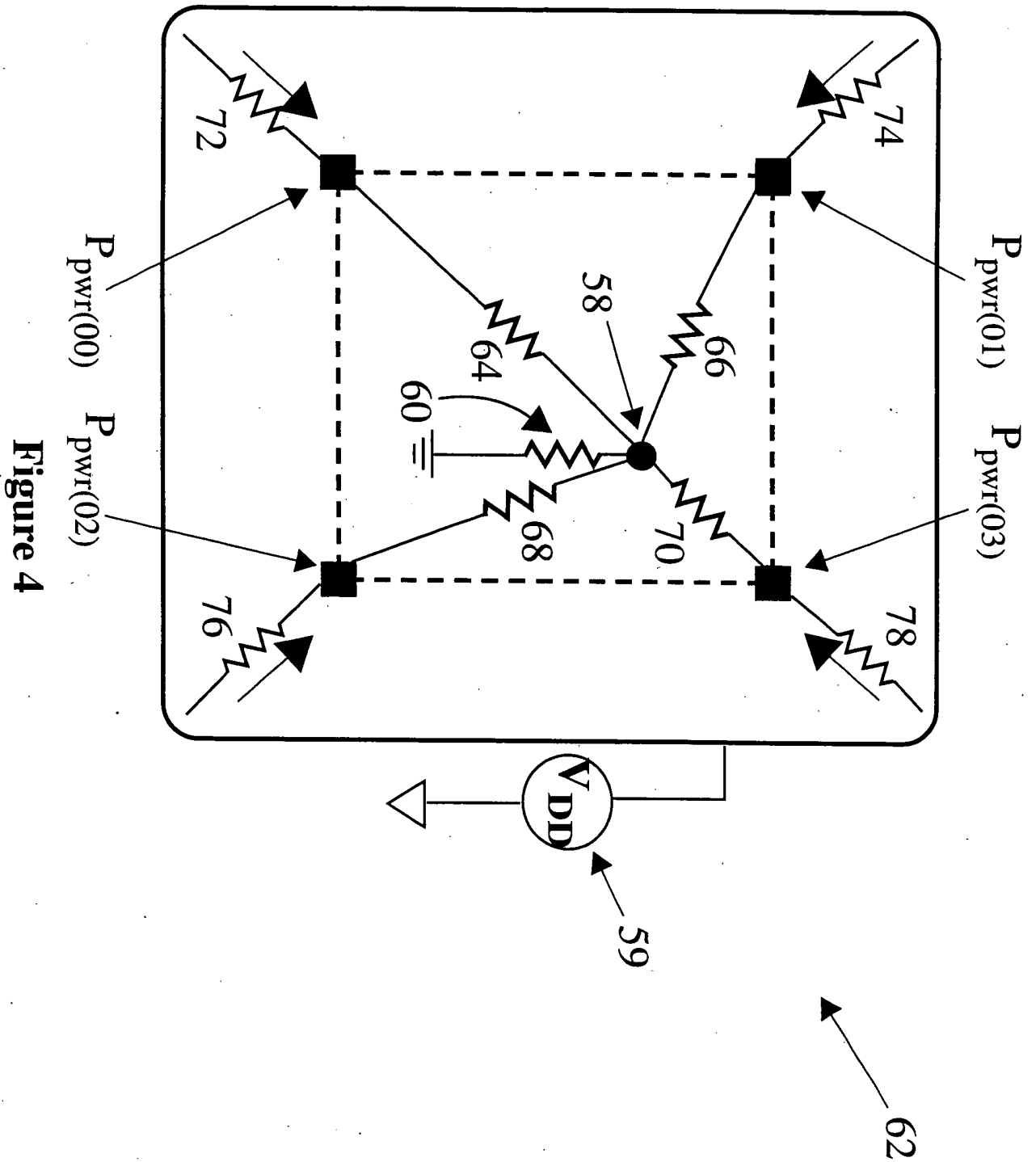
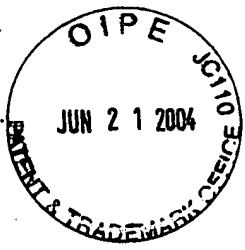
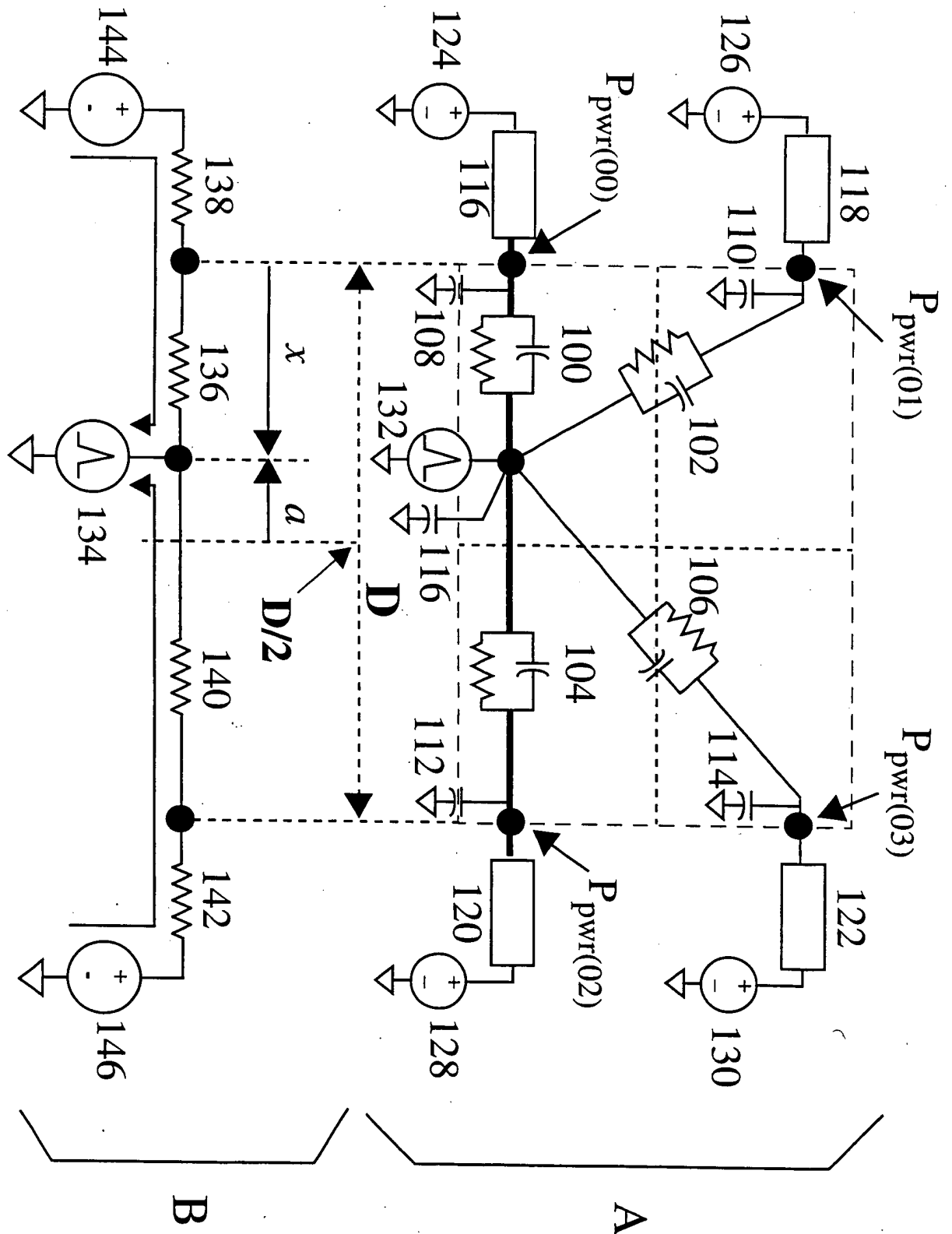


Figure 4



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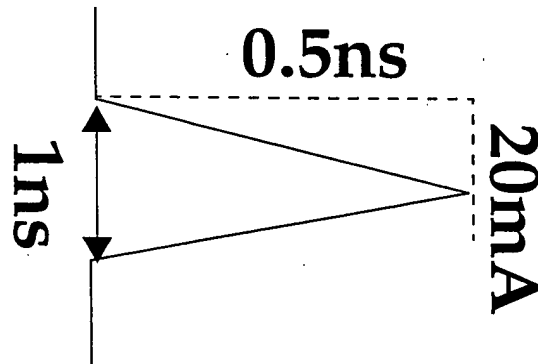


Figure 6

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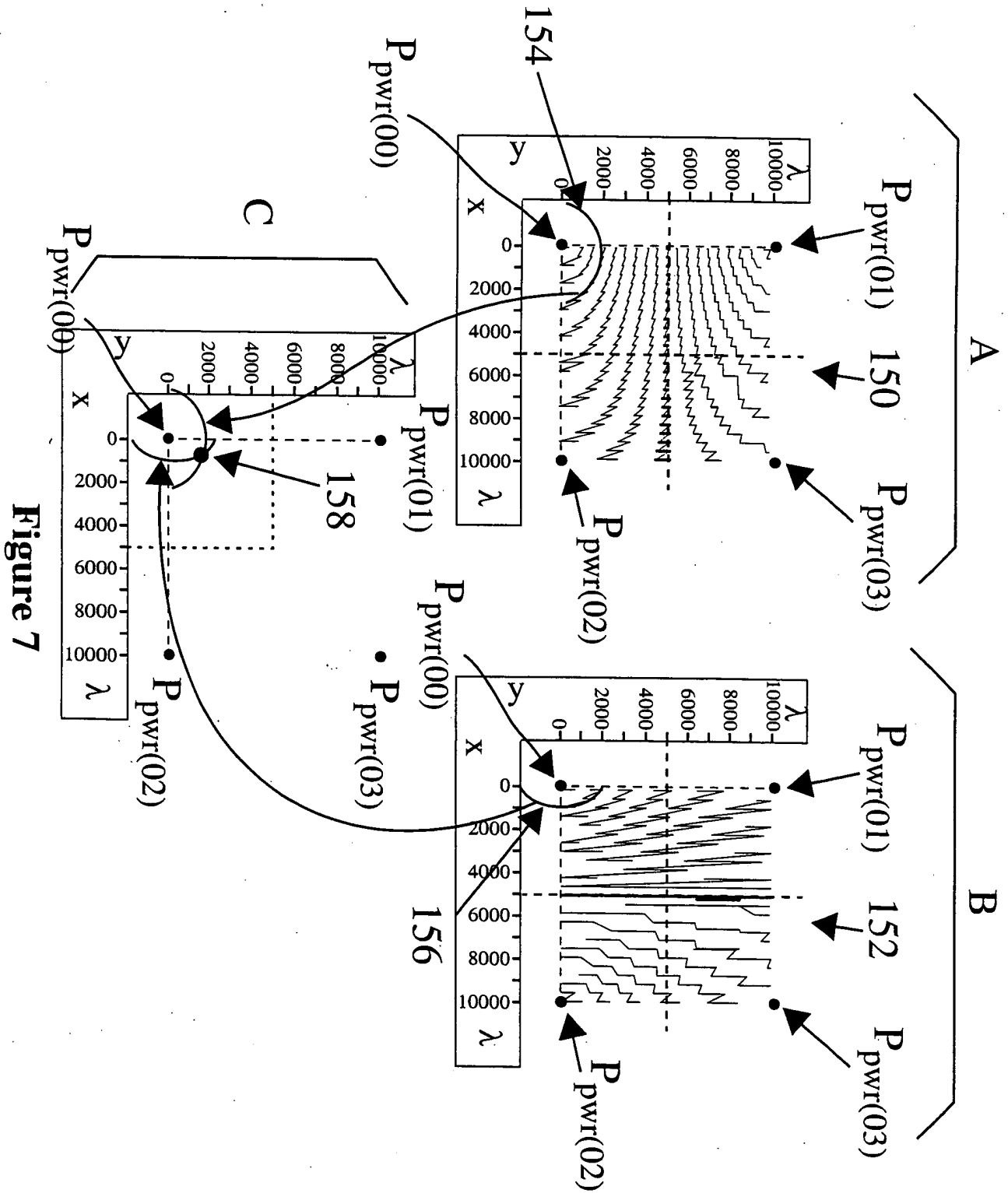


Figure 7

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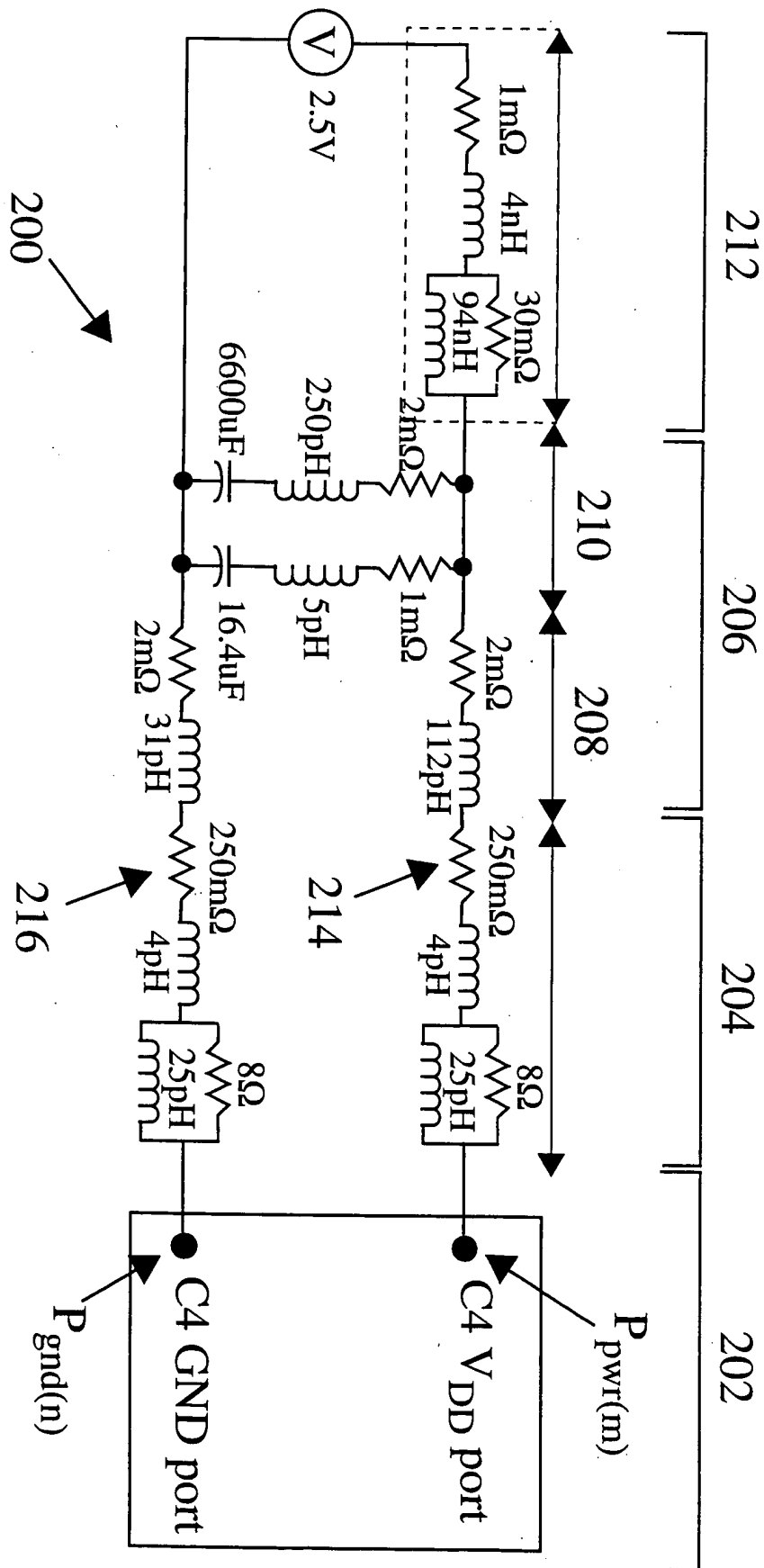


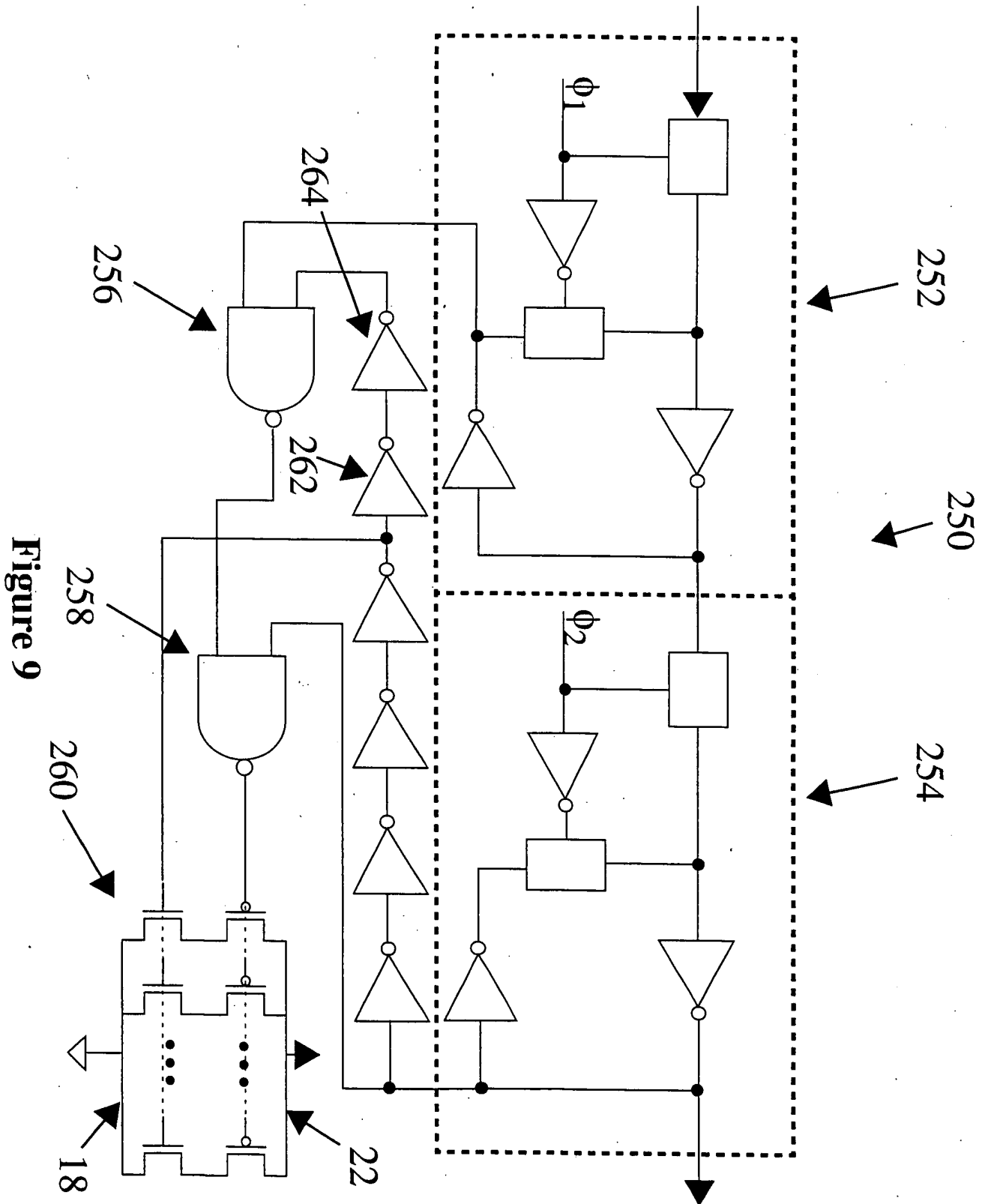
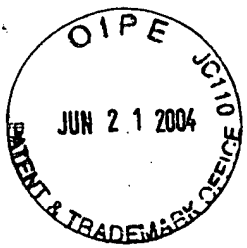
Figure 8



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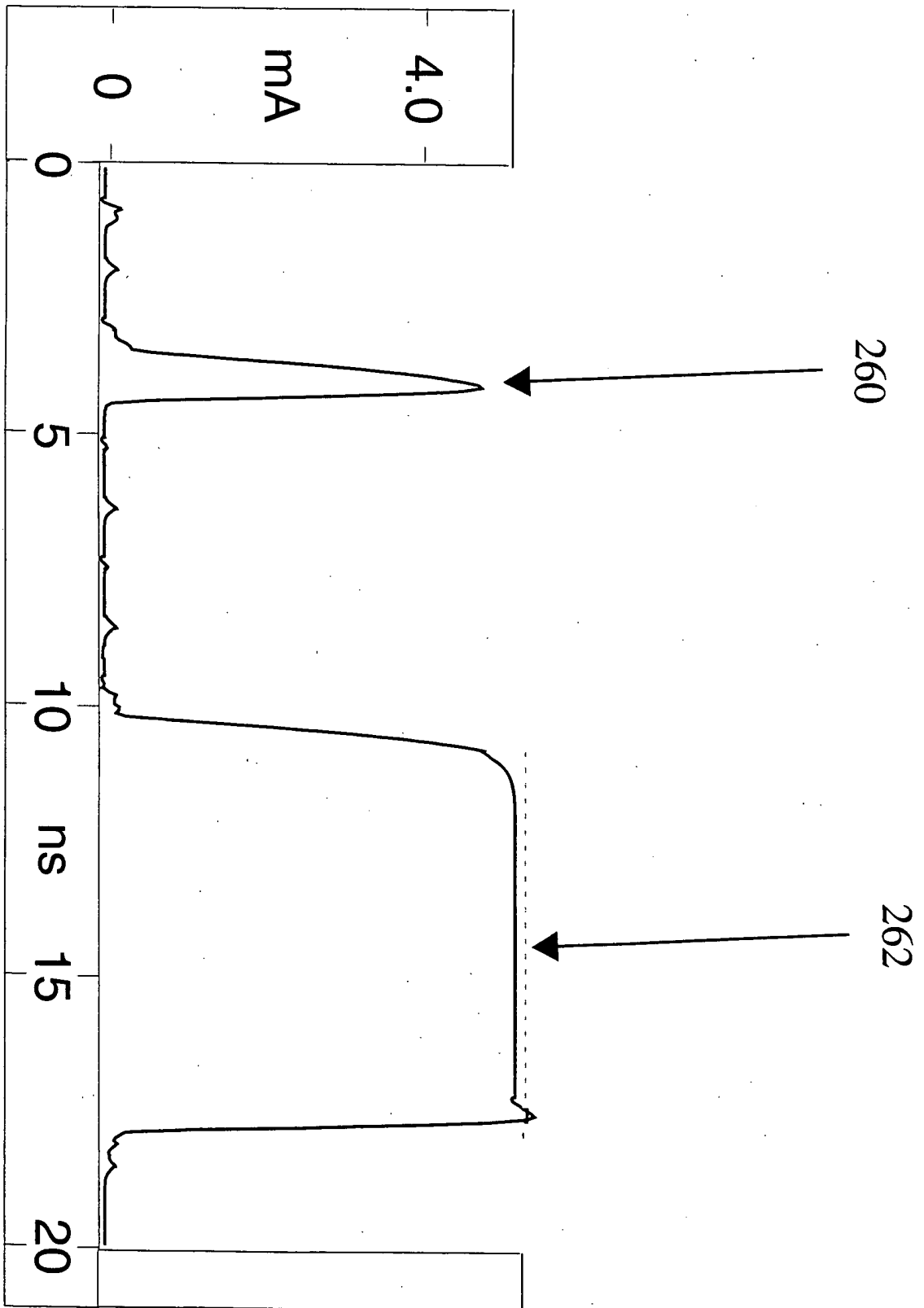


Figure 10

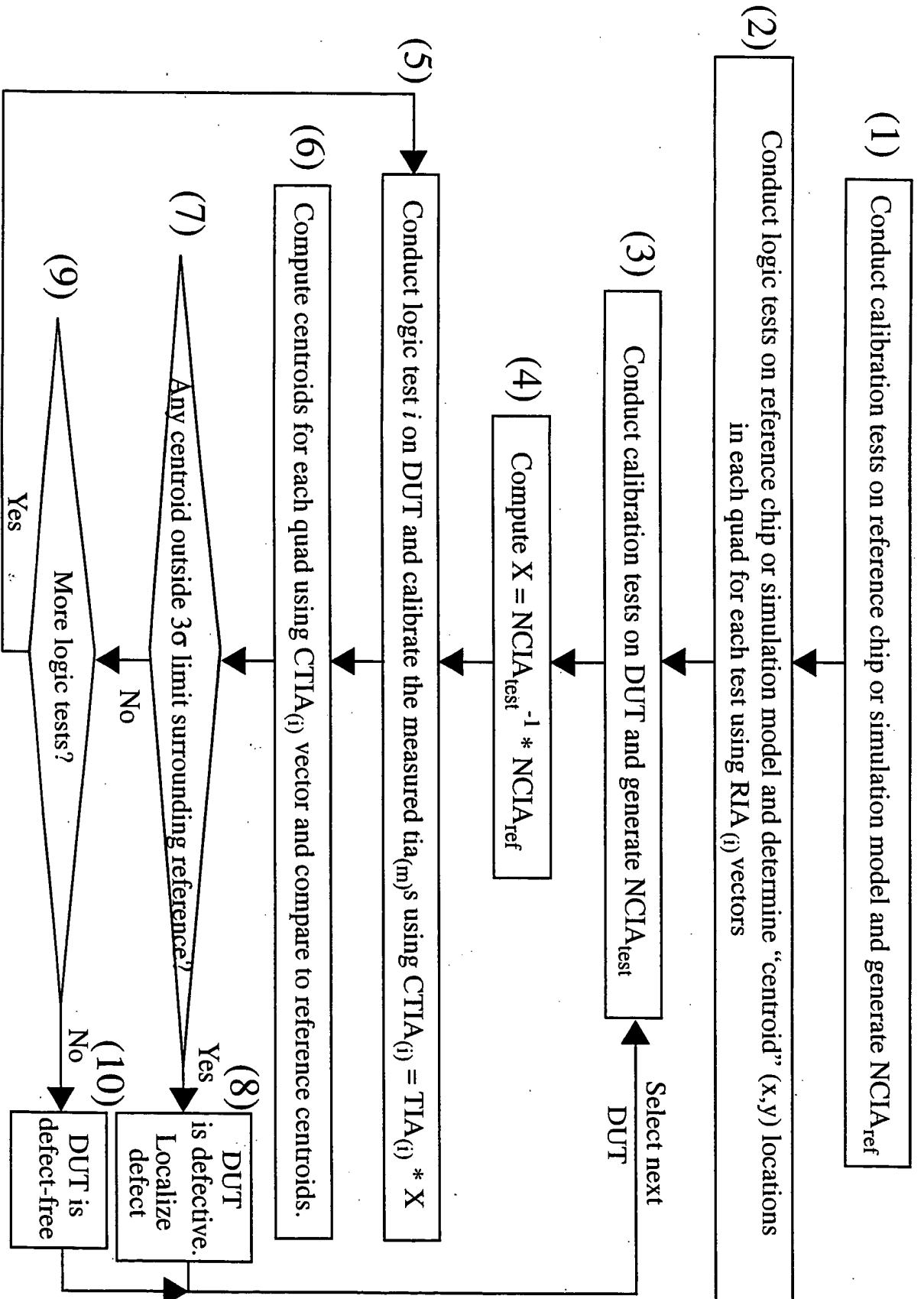


Figure 11

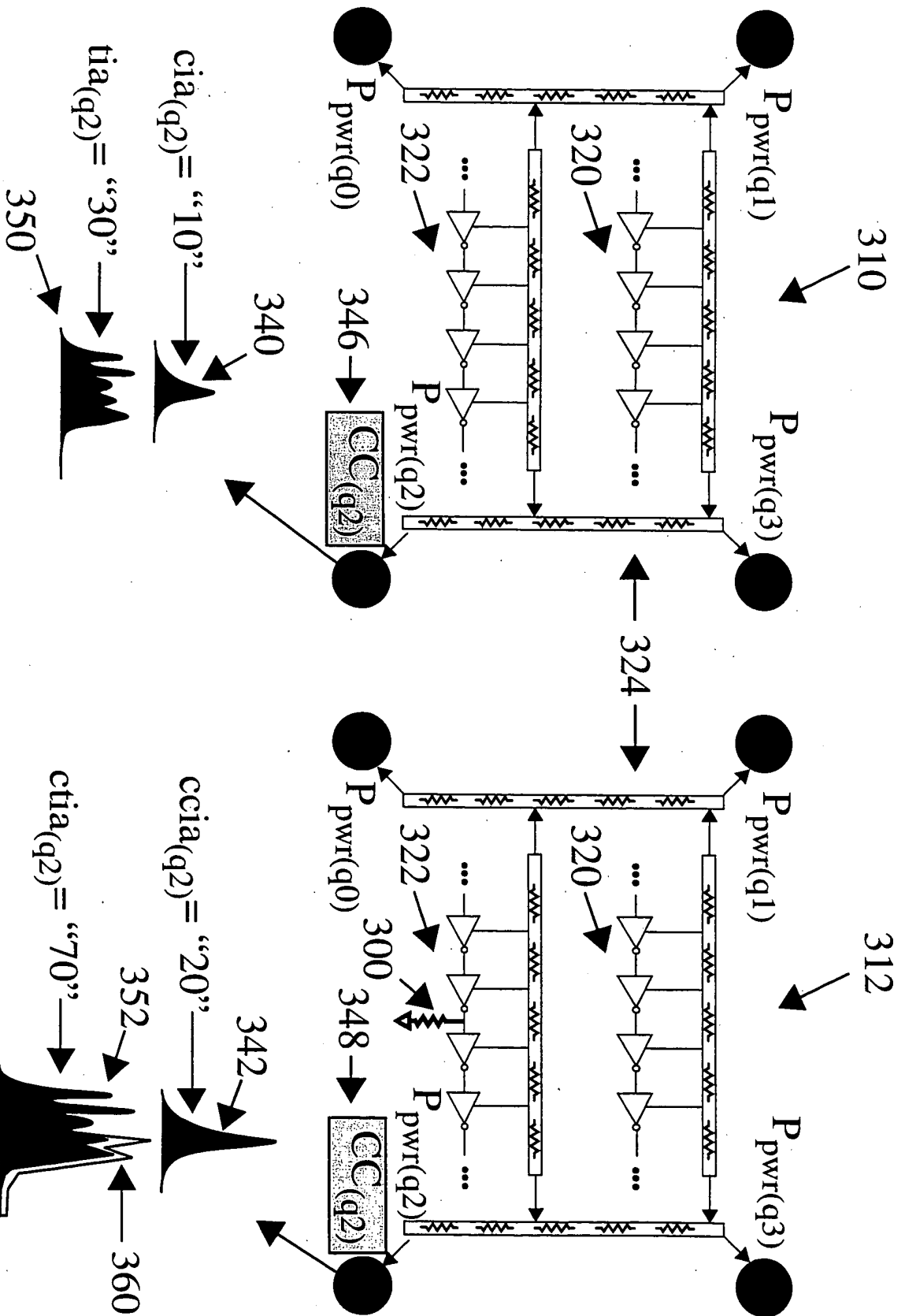
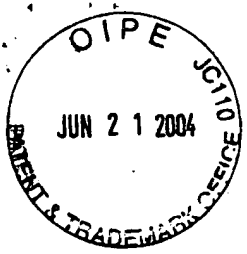


Figure 12